1,048,576 WORD x 4 BIT DYNAMIC RAM

* This is advanced information and specifications are subject to change without notice.

DESCRIPTION

The TC514400J/Z is the new generation dynamic RAM organized 1,048,576 words by 4 bits. The TC514400J/Z utilizes TOSHIBA's CMOS Silicon gate process technology as well as advanced circuit techniques to provide wide operating margins, both internally and to the system user. Multiplexed address inputs permit the TC514400J/Z to be packaged in a standard 26/20 pin plastic SOJ and 20 pin plastic ZIP. The package size provides high system bit densities and is compatible with widely available automated testing and insertion equipment. System oriented features include single power supply of 5V±10% tolerance, direct interfacing capability with high performance logic families such as Schottky TTL.

FEATURES

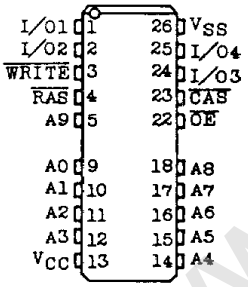
- 1,048,576 word by 4 bit organization
- Fast access time and cycle time

		TC514400J/Z-80/-10	
t_{RAC}	$\overline{RAS}$ Access Time	80ns	100ns
t_{AA}	Column Address Access Time	40ns	50ns
t_{CAC}	$\overline{CAS}$ Access Time	20ns	25ns
t_{RC}	Cycle Time	150ns	180ns
t_{PC}	Fast Page Mode Cycle Time	50ns	60ns

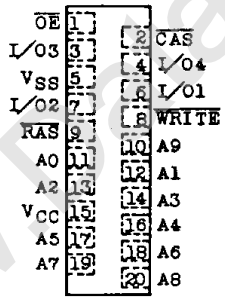
- Single power supply of 5V±10% with a built-in V_{BB} generator
- Low Power
  578mW MAX. Operating (TC514400J/Z-80)
  495mW MAX. Operating (TC514400J/Z-10)
  5.5mW MAX. Standby
- Outputs unlatched at cycle end allows two-dimensional chip selection
- Read-Modify-Write, $\overline{CAS}$ before $\overline{RAS}$ refresh, $\overline{RAS}$-only refresh, Hidden refresh and Fast Page Mode capability
- All inputs and outputs TTL compatible
- 1024 refresh cycles/16ms
- Package Plastic SOJ: TC514400J
  Plastic ZIP: TC514400Z

PIN CONNECTION (TOP VIEW)

Plastic SOJ



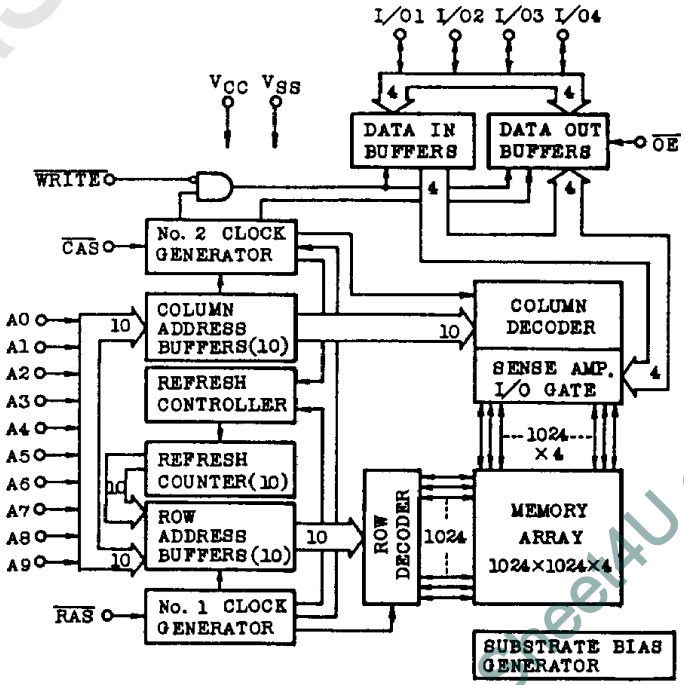
Plastic ZIP



PIN NAMES

A0 ∿ A9	Address Inputs
$\overline{RAS}$	Row Address Strobe
$\overline{CAS}$	Column Address Strobe
$\overline{WRITE}$	Read/Write Input
$\overline{OE}$	Output Enable
I/O1 ∿ I/O4	Data Input/Output
V_{CC}	Power (+5V)
V_{SS}	Ground

BLOCK DIAGRAM



ABSOLUTE MAXIMUM RATINGS

ITEM	SYMBOL	RATING	UNITS	NOTE
Input Voltage	V_{IN}	-1 ~ 7	V	1
Output Voltage	V_{OUT}	-1 ~ 7	V	1
Power Supply Voltage	V_{CC}	-1 ~ 7	V	1
Operating Temperature	T_{OPR}	0 ~ 70	°C	1
Storage Temperature	T_{STG}	-55 ~ 150	°C	1
Soldering Temperature · Time	T_{SOLDER}	260 · 10	°C·sec	1
Power Dissipation	P_D	600	mW	1
Short Circuit Output Current	I_{OUT}	50	mA	1

RECOMMENDED DC OPERATING CONDITIONS (T_a=0 ~ 70°C)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT	NOTE
V_{CC}	Supply Voltage	4.5	5.0	5.5	V	2
V_{IH}	Input High Voltage	2.4	-	6.5	V	2
V_{IL}	Input Low Voltage	-1.0	-	0.8	V	2

DC ELECTRICAL CHARACTERISTICS (V_{CC}=5V±10%, T_a=0 ~ 70°C)

SYMBOL	PARAMETER		MIN.	MAX.	UNITS	NOTES
I_{CC1}	OPERATING CURRENT Average Power Supply Operating Current ($\overline{RAS}$, $\overline{CAS}$, Address Cycling: t_{RC}=t_{RC} MIN.)	TC514400J/Z-80	-	105	mA	3,4,5
		TC514400J/Z-10	-	90		
I_{CC2}	STANDBY CURRENT Power Supply Standby Current ($\overline{RAS}$=$\overline{CAS}$=V_{IH})		-	2	mA	
I_{CC3}	$\overline{RAS}$ ONLY REFRESH CURRENT Average Power Supply Current, $\overline{RAS}$ Only Mode ($\overline{RAS}$ Cycling, $\overline{CAS}$=V_{IH}: t_{RC}=t_{RC} MIN.)	TC514400J/Z-80	-	105	mA	3,5
		TC514400J/Z-10	-	90		
I_{CC4}	FAST PAGE MODE CURRENT Average Power Supply Current, Fast Page Mode ($\overline{RAS}$=V_{IL}, $\overline{CAS}$, Address Cycling: t_{PC}=t_{PC} MIN.)	TC514400J/Z-80	-	70	mA	3,4,5
		TC514400J/Z-10	-	60		
I_{CC5}	STANDBY CURRENT Power Supply Standby Current ($\overline{RAS}$=$\overline{CAS}$=V_{CC}-0.2V)		-	1	mA	
I_{CC6}	$\overline{CAS}$ BEFORE $\overline{RAS}$ REFRESH CURRENT Average Power Supply Current, $\overline{CAS}$ Before $\overline{RAS}$ Mode ($\overline{RAS}$, $\overline{CAS}$ Cycling: t_{RC}=t_{RC} MIN.)	TC514400J/Z-80	-	105	mA	3
		TC514400J/Z-10	-	90		
$I_{I(L)}$	INPUT LEAKAGE CURRENT Input Leakage Current, any input (0V ≦ V_{IN} ≦ 6.5V, All Other Pins Not Under Test=0V)		-10	10	μA	
$I_{O(L)}$	OUTPUT LEAKAGE CURRENT (D_{OUT} is disabled, 0V ≦ V_{OUT} ≦ 5.5V)		-10	10	μA	
V_{OH}	OUTPUT LEVEL Output "H" Level Voltage (I_{OUT}=-5mA)		2.4	-	V	
V_{OL}	OUTPUT LEVEL Output "L" Level Voltage (I_{OUT}=4.2mA)		-	0.4	V	

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(V_{CC}=5V±10%, Ta=0∿70°C) (Notes 6, 7, 8)

SYMBOL	PARAMETER	TC514400J/Z -80		TC514400J/Z -10		UNIT	NOTES
		MIN.	MAX.	MIN.	MAX.		
t_{RC}	Random Read or Write Cycle Time	150	-	180	-	ns	
t_{RMW}	Read-Modify-Write Cycle Time	205	-	245	-	ns	
t_{PC}	Fast Page Mode Cycle Time	50	-	60	-	ns	
t_{PRMW}	Fast Page Mode Read-Modify-Write Cycle Time	105	-	125	-	ns	
t_{RAC}	Access Time from $\overline{RAS}$	-	80	-	100	ns	9.14.15
t_{CAC}	Access Time from $\overline{CAS}$	-	20	-	25	ns	9,14
t_{AA}	Access Time from Column Address	-	40	-	50	ns	9,15
t_{CPA}	Access Time from $\overline{CAS}$ Precharge	-	45	-	55	ns	9
t_{CLZ}	$\overline{CAS}$ to Output in Low-Z	0	-	0	-	ns	9
t_{OFF}	Output Buffer Turn-off Delay	0	20	0	20	ns	10
t_T	Transition Time (Rise and Fall)	3	50	3	50	ns	8
t_{RP}	$\overline{RAS}$ Precharge Time	60	-	70	-	ns	
t_{RAS}	$\overline{RAS}$ Pulse Width	80	10,000	100	10,000	ns	
t_{RASP}	$\overline{RAS}$ Pulse Width (Fast Page Mode)	80	200,000	100	200,000	ns	
t_{RSH}	$\overline{RAS}$ Hold Time	20	-	25	-	ns	
t_{CSH}	$\overline{CAS}$ Hold Time	80	-	100	-	ns	
t_{RHCP}	$\overline{CAS}$ Precharge to $\overline{RAS}$ Hold Time	45	-	55	-	ns	
t_{CAS}	$\overline{CAS}$ Pulse Width	20	10,000	25	10,000	ns	
t_{RCD}	$\overline{RAS}$ to $\overline{CAS}$ Delay Time	20	60	25	75	ns	14
t_{RAD}	$\overline{RAS}$ to Column Address Delay Time	15	40	20	50	ns	15
t_{CRP}	$\overline{CAS}$ to $\overline{RAS}$ Precharge Time	5	-	10	-	ns	
t_{CP}	$\overline{CAS}$ Precharge Time	10	-	10	-	ns	
t_{ASR}	Row Address Set-Up Time	0	-	0	-	ns	
t_{RAH}	Row Address Hold Time	10	-	15	-	ns	
t_{ASC}	Column Address Set-Up Time	0	-	0	-	ns	
t_{CAH}	Column Address Hold Time	15	-	20	-	ns	
t_{AR}	Column Address Hold Time referenced to $\overline{RAS}$	60	-	75	-	ns	
t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	40	-	50	-	ns	
t_{RCS}	Read Command Set-Up Time	0	-	0	-	ns	
t_{RCH}	Read Command Hold Time	0	-	0	-	ns	11

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS (Continued)

SYMBOL	PARAMETER	TC514400J/Z-80		TC514400J/Z-10		UNITS	NOTES
		MIN.	MAX.	MIN.	MAX.		
t_{RRH}	Read Command Hold Time referenced to $\overline{RAS}$	0	-	0	-	ns	11
t_{WCH}	Write Command Hold Time	15	-	20	-	ns	
t_{WCR}	Write Command Hold Time referenced to $\overline{RAS}$	60	-	75	-	ns	
t_{WP}	Write Command Pulse Width	15	-	20	-	ns	
t_{RWL}	Write Command to $\overline{RAS}$ Lead Time	20	-	25	-	ns	
t_{CWL}	Write Command to $\overline{CAS}$ Lead Time	20	-	25	-	ns	
t_{DS}	Data Set-Up Time	0	-	0	-	ns	12
t_{DH}	Data Hold Time	15	-	20	-	ns	12
t_{DHR}	Data Hold Time referenced to $\overline{RAS}$	60	-	75	-	ns	
t_{REF}	Refresh Period	-	16	-	16	ms	
t_{WCS}	Write Command Set-Up Time	0	-	0	-	ns	13
t_{CWD}	$\overline{CAS}$ to $\overline{WRITE}$ Delay Time	50	-	60	-	ns	13
t_{RWD}	$\overline{RAS}$ to $\overline{WRITE}$ Delay Time	110	-	135	-	ns	13
t_{AWD}	Column Address to $\overline{WRITE}$ Delay Time	70	-	85	-	ns	13
t_{CPWD}	$\overline{CAS}$ Precharge to $\overline{WRITE}$ Delay Time (Fast Page Mode)	75	-	90	-	ns	13
t_{CSR}	$\overline{CAS}$ Set-Up Time ($\overline{CAS}$ before $\overline{RAS}$ Cycle)	5	-	5	-	ns	
t_{CHR}	$\overline{CAS}$ Hold Time ($\overline{CAS}$ before $\overline{RAS}$ Cycle)	15	-	20	-	ns	
t_{RPC}	$\overline{RAS}$ to $\overline{CAS}$ Precharge Time	0	-	0	-	ns	
t_{CPT}	$\overline{CAS}$ Precharge Time ($\overline{CAS}$ before $\overline{RAS}$ Counter Test Cycle)	40	-	50	-	ns	
t_{ROH}	$\overline{RAS}$ Hold Time referenced to $\overline{OE}$	10	-	20	-	ns	
t_{OEA}	$\overline{OE}$ Access Time	-	20	-	25	ns	
t_{OED}	$\overline{OE}$ to Data Delay	20	-	25	-	ns	
t_{OEZ}	Output Buffer Turn Off Delay Time from $\overline{OE}$	0	20	0	20	ns	10
t_{OEH}	$\overline{OE}$ Command Hold Time	20	-	25	-	ns	
t_{WTS}	Write Command Set-Up Time(Test Mode In)	10	-	10	-	ns	
t_{WTH}	Write Command Hold Time (Test Mode In)	10	-	10	-	ns	
t_{WRP}	$\overline{WRITE}$ to $\overline{RAS}$ Precharge Time ($\overline{CAS}$ before $\overline{RAS}$ Cycle)	10	-	10	-	ns	
t_{WRH}	$\overline{WRITE}$ to $\overline{RAS}$ Hold Time ($\overline{CAS}$ before $\overline{RAS}$ Cycle)	10	-	10	-	ns	

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS IN THE TEST MODE

SYMBOL	PARAMETER	TC514400J/Z -80		TC514400J/Z -10		UNIT	NOTES
		MIN.	MAX.	MIN.	MAX.		
t_{RC}	Random Read or Write Cycle Time	155	-	185	-	ns	
t_{PC}	Fast Page Mode Cycle Time	55	-	65	-	ns	
t_{RAC}	Access Time from $\overline{RAS}$	-	85	-	105	ns	9,14,15
t_{CAC}	Access Time from $\overline{CAS}$	-	25	-	30	ns	9,14
t_{AA}	Access Time from Column Address	-	45	-	55	ns	9,15
t_{CPA}	Access Time from $\overline{CAS}$ Precharge	-	50	-	60	ns	9
t_{RAS}	$\overline{RAS}$ Pulse Width	85	10,000	105	10,000	ns	
t_{RASP}	$\overline{RAS}$ Pulse Width(Fast Page Mode)	85	200,000	105	200,000	ns	
t_{RSH}	$\overline{RAS}$ Hold Time	25	-	30	-	ns	
t_{CSH}	$\overline{CAS}$ Hold Time	85	-	105	-	ns	
t_{RHCP}	$\overline{CAS}$ Precharge to $\overline{RAS}$ Hold Time	50	-	60	-	ns	
t_{CAS}	$\overline{CAS}$ Pulse Width	25	10,000	30	10,000	ns	
t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	45	-	55	-	ns	

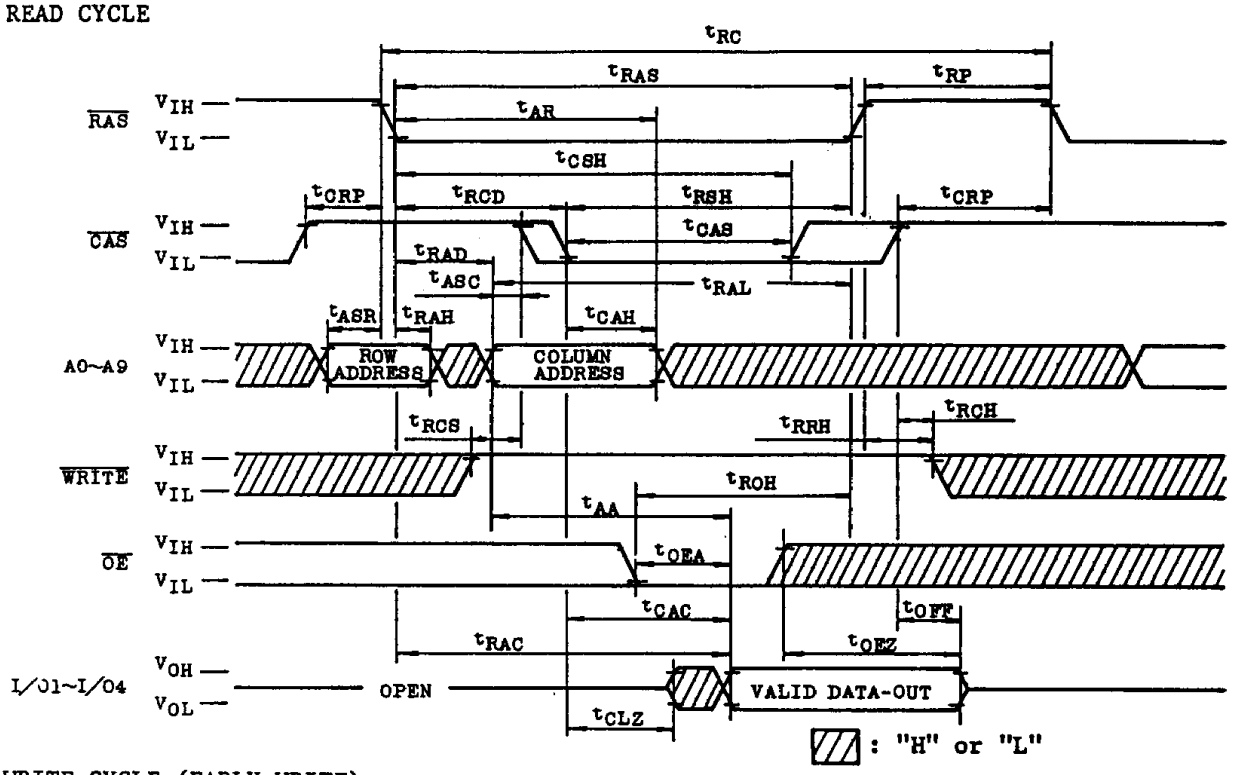
CAPACITANCE (V_{CC}=5V±10%, f=1MHz, Ta=0~70°C)

SYMBOL	PARAMETER	MIN.	MAX.	UNIT
C_{I1}	Input Capacitance (A0~A9)	-	5	pF
C_{I2}	Input Capacitance ($\overline{RAS}$, $\overline{CAS}$, $\overline{WRITE}$, $\overline{OE}$)	-	7	pF
C_O	Output Capacitance (I/O1~I/O4)	-	7	pF

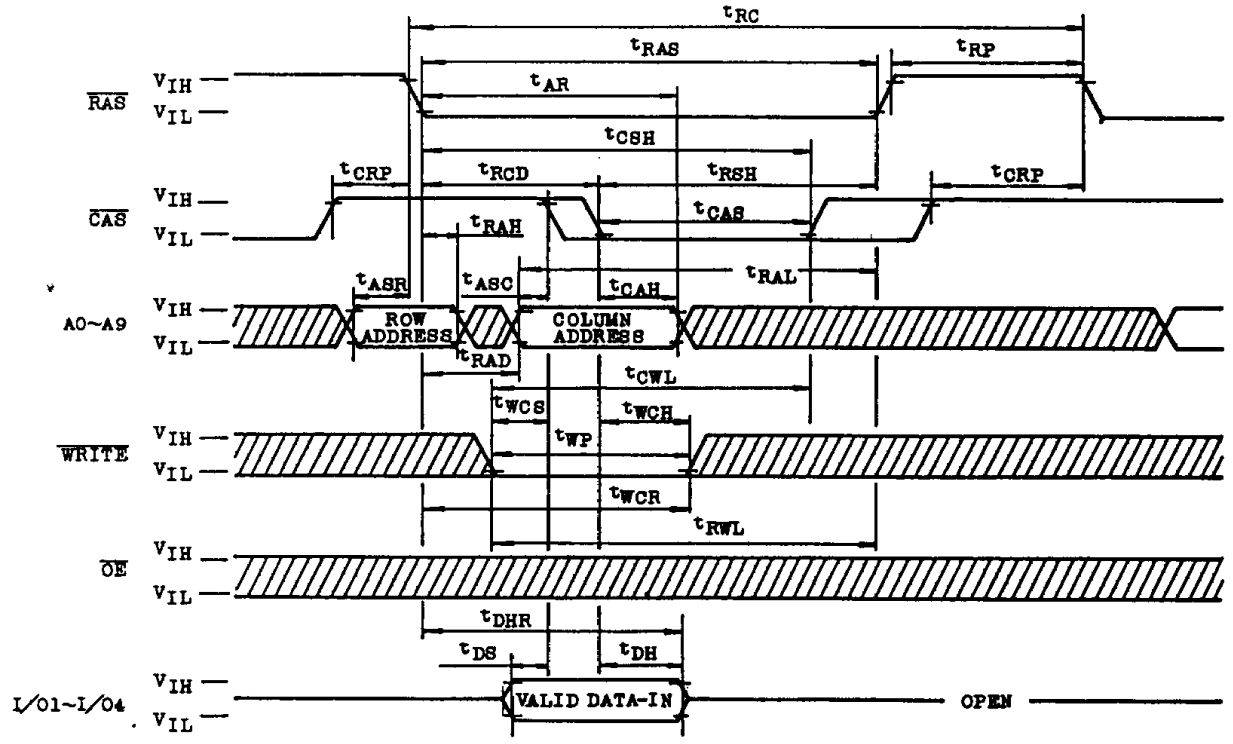
NOTES:

1. Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device.
2. All voltages are referenced to V_{SS}.
3. I_{CC1}, I_{CC3}, I_{CC4}, I_{CC6} depend on cycle rate.
4. I_{CC1}, I_{CC4} depend on output loading. Specified values are obtained with the output open.
5. Column address can be changed once or less while $\overline{RAS}=V_{IL}$ and $\overline{CAS}=V_{IH}$.
6. An initial pause of 200μs is required after power-up followed by 8 $\overline{RAS}$ only refresh cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 $\overline{CAS}$ before $\overline{RAS}$ refresh cycles instead of 8 $\overline{RAS}$ only refresh cycles are required.
7. AC measurements assume $t_T=5ns$.
8. V_{IH}(min.) and V_{IL}(max.) are reference levels for measuring timing of input signals. Also, transition times are measured between V_{IH} and V_{IL}.
9. Measured with a load equivalent to 2 TTL loads and 100pF.
10. t_{OFF}(max.) and t_{OEZ}(max.) define the time at which the output achieves the open circuit condition and are not referenced to output voltage levels.
11. Either t_{RCH} or t_{RRH} must be satisfied for a read cycle.
12. These parameters are referenced to $\overline{CAS}$ leading edge in early write cycles and to $\overline{WRITE}$ leading edge in read-modify-write cycles.
13. t_{WCS}, t_{RWD}, t_{CWD}, t_{AWD} and t_{CPWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If $t_{WCS} \geq t_{WCS}$ (min.) the cycle is an early write cycle and data out pin will remain open circuit (high impedance) through the entire cycle; If $t_{RWD} \geq t_{RWD}$ (min.), $t_{CWD} \geq t_{CWD}$ (min.), $t_{AWD} \geq t_{AWD}$ (min.) and $t_{CPWD} \geq t_{CPWD}$ (min.) (Fast Page Mode), the cycle is a read-modify-write cycle and data out will contain data read from the selected cell: If neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
14. Operation within the t_{RCD}(max.) limit insures that t_{RAC}(max.) can be met. t_{RCD}(max.) is specified as a reference point only: If t_{RCD} is greater than the specified t_{RCD}(max.) limit, then access time is controlled by t_{CAC}.
15. Operation within the t_{RAD}(max.) limit insures that t_{RAC}(max.) can be met. t_{RAD}(max.) is specified as a reference point only: If t_{RAD} is greater than the specified t_{RAD}(max.) limit, then access time is controlled by t_{AA}.

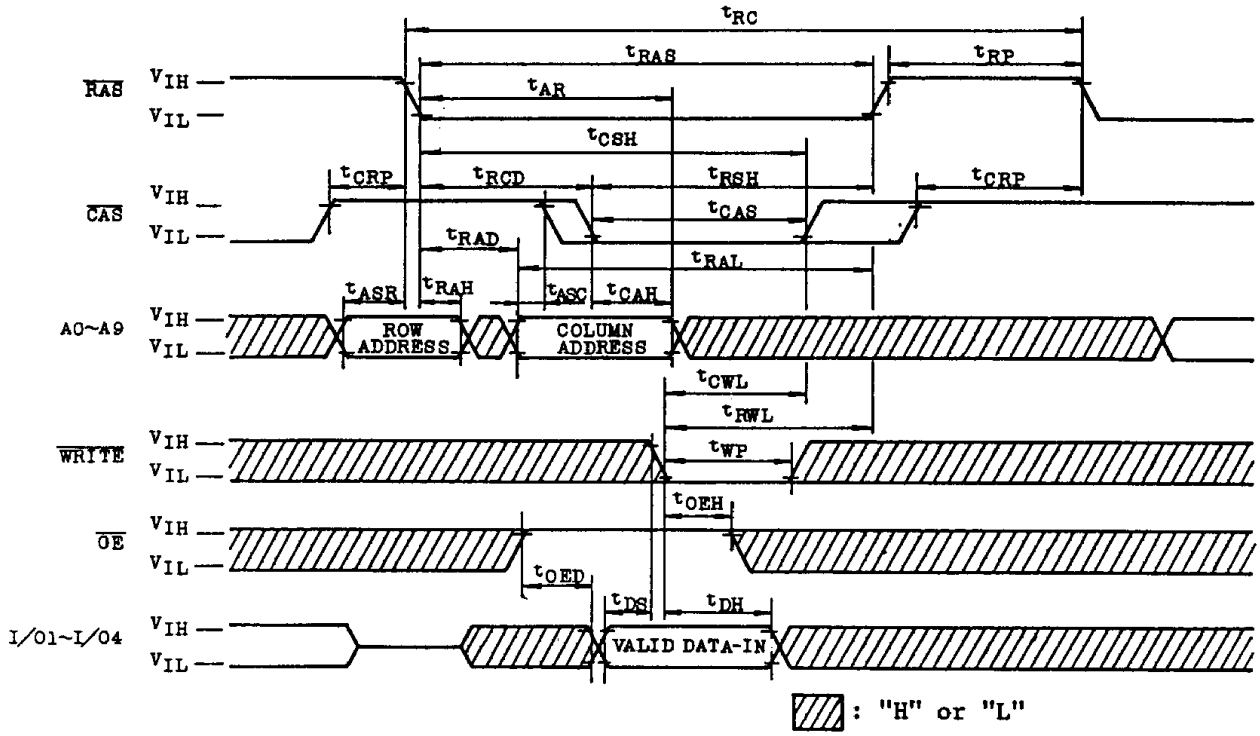
READ CYCLE



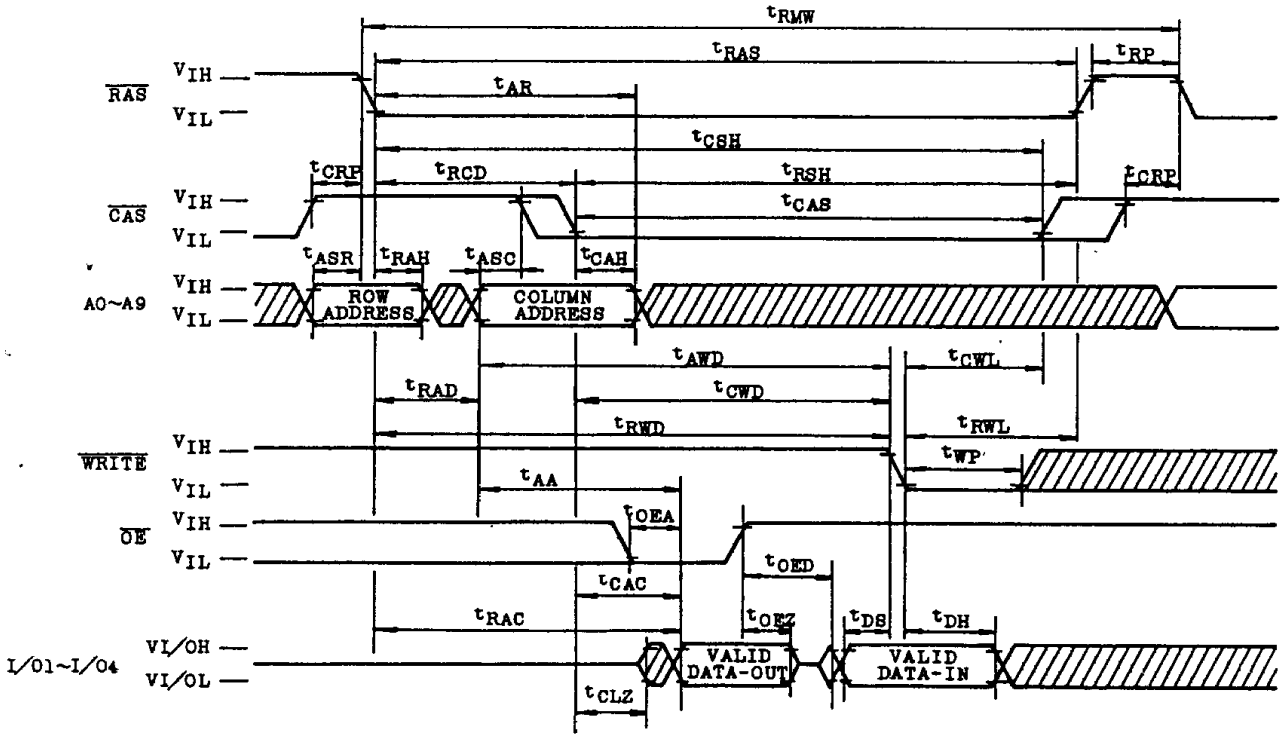
WRITE CYCLE (EARLY WRITE)



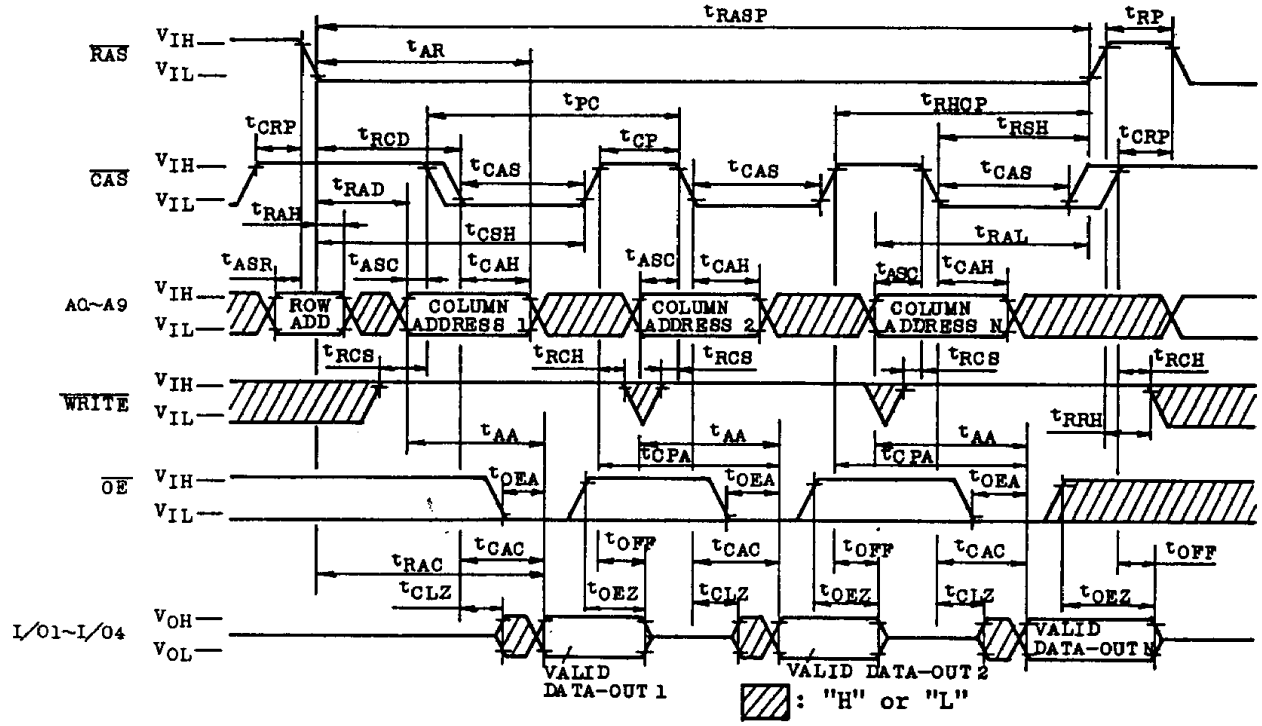
WRITE CYCLE ($\overline{OE}$ CONTROLLED WRITE)



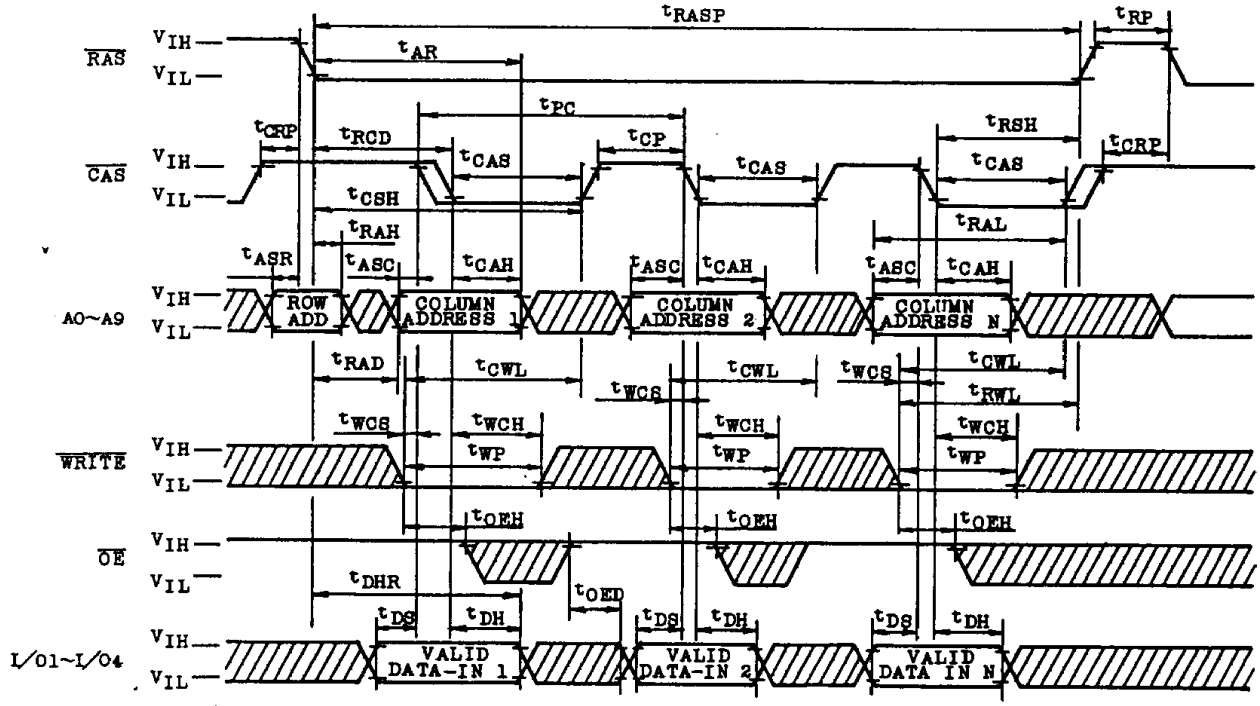
READ-MODIFY-WRITE CYCLE



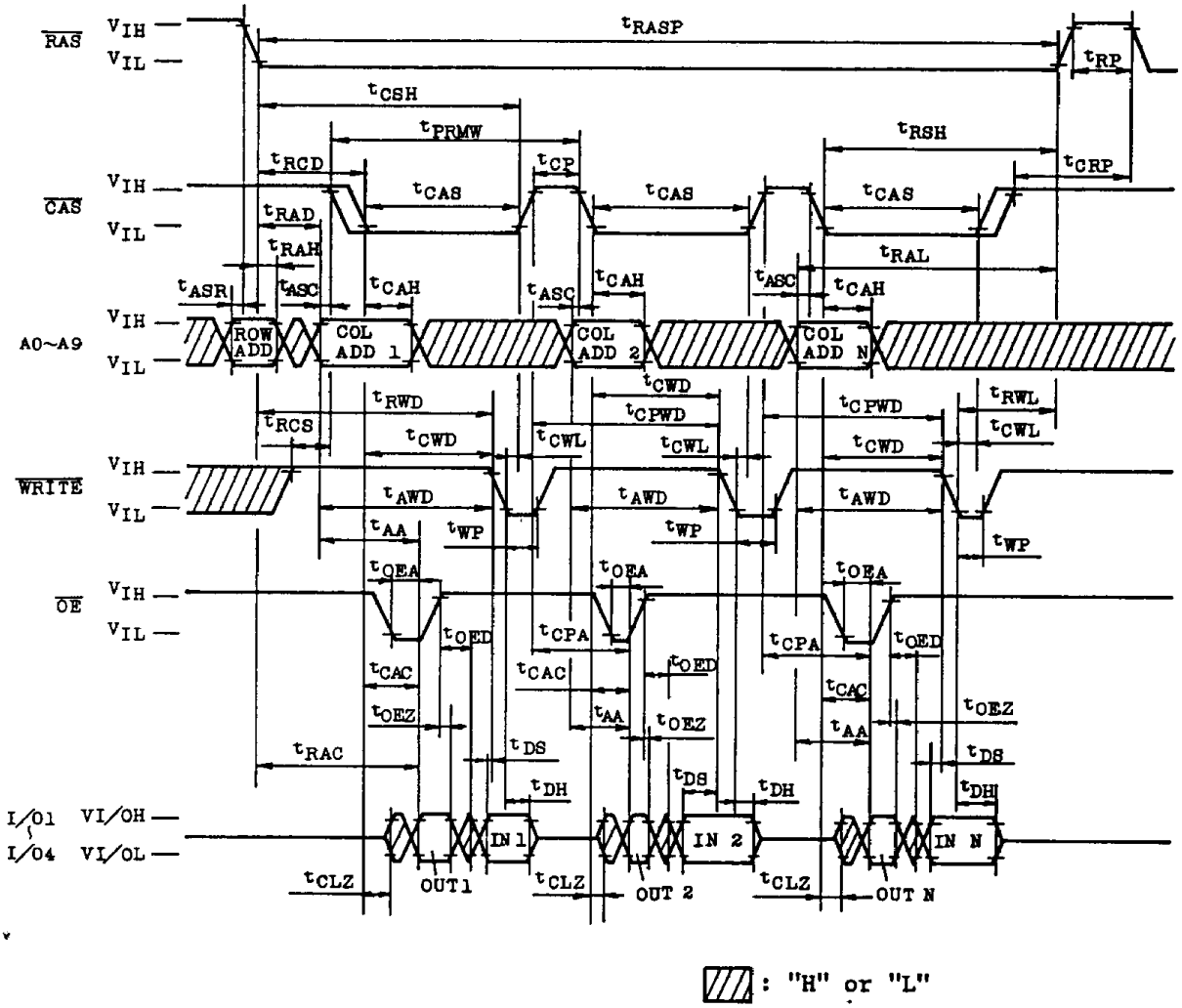
FAST PAGE MODE READ CYCLE



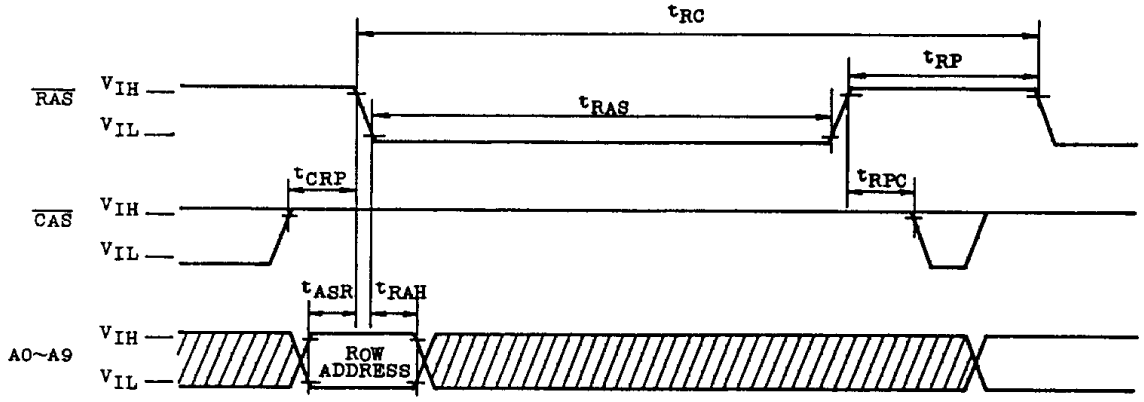
FAST PAGE MODE WRITE CYCLE



FAST PAGE MODE READ-MODIFY-WRITE CYCLE

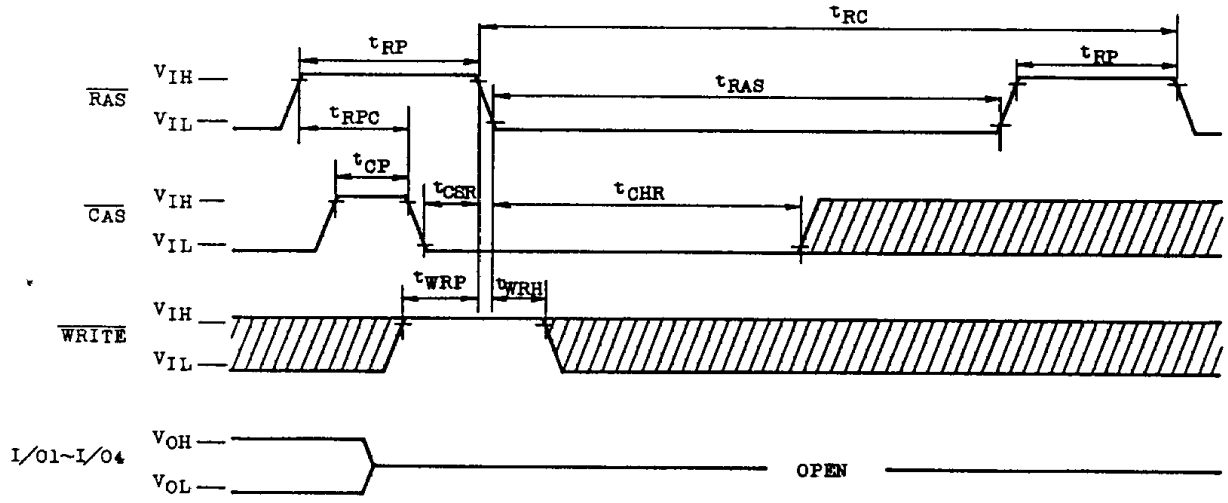


$\overline{RAS}$ ONLY REFRESH CYCLE



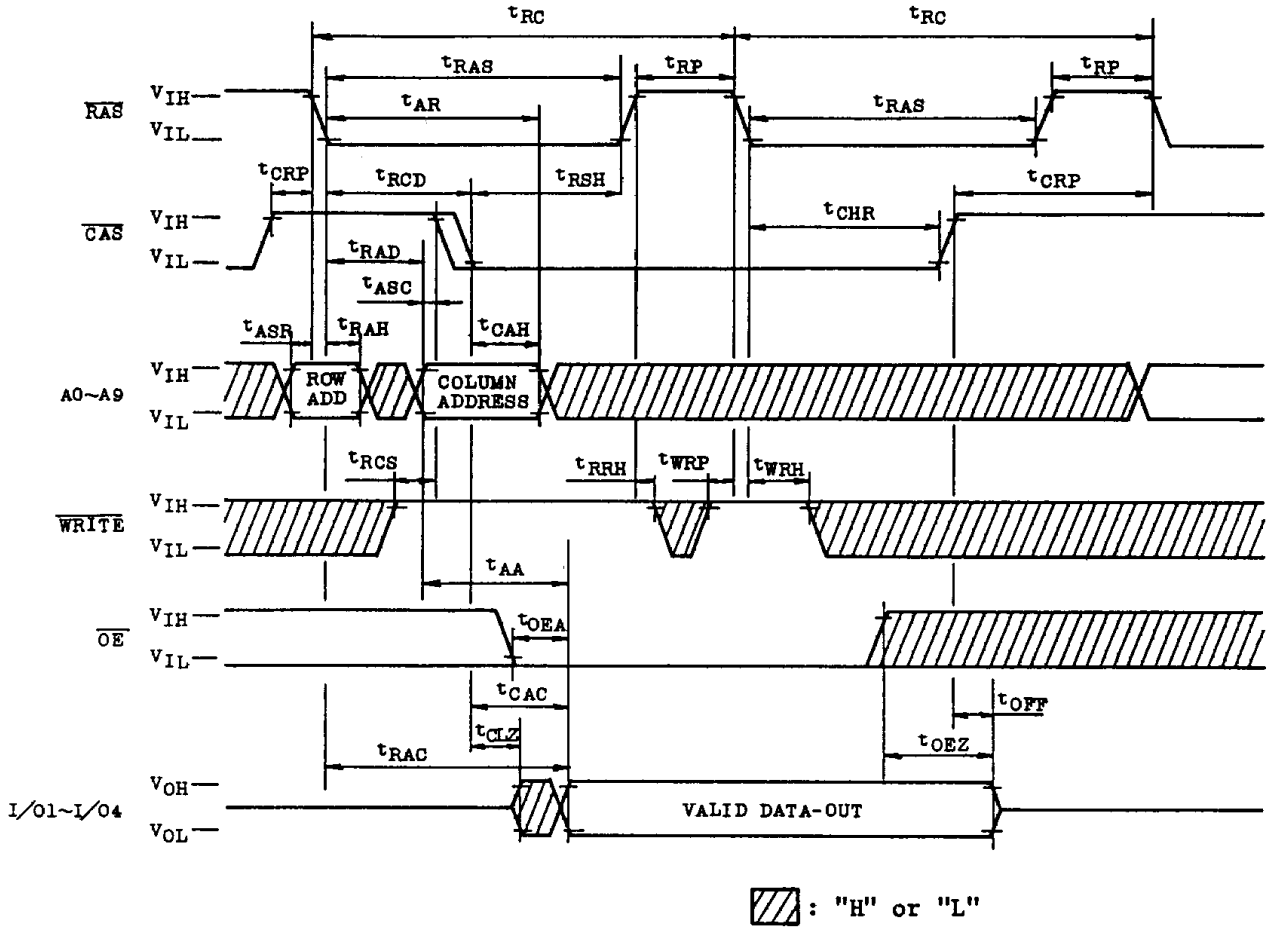
Note: $\overline{WRITE}$, $\overline{OE}$="H" or "L" ▨ : "H" or "L"

$\overline{CAS}$ BEFORE $\overline{RAS}$ REFRESH CYCLE

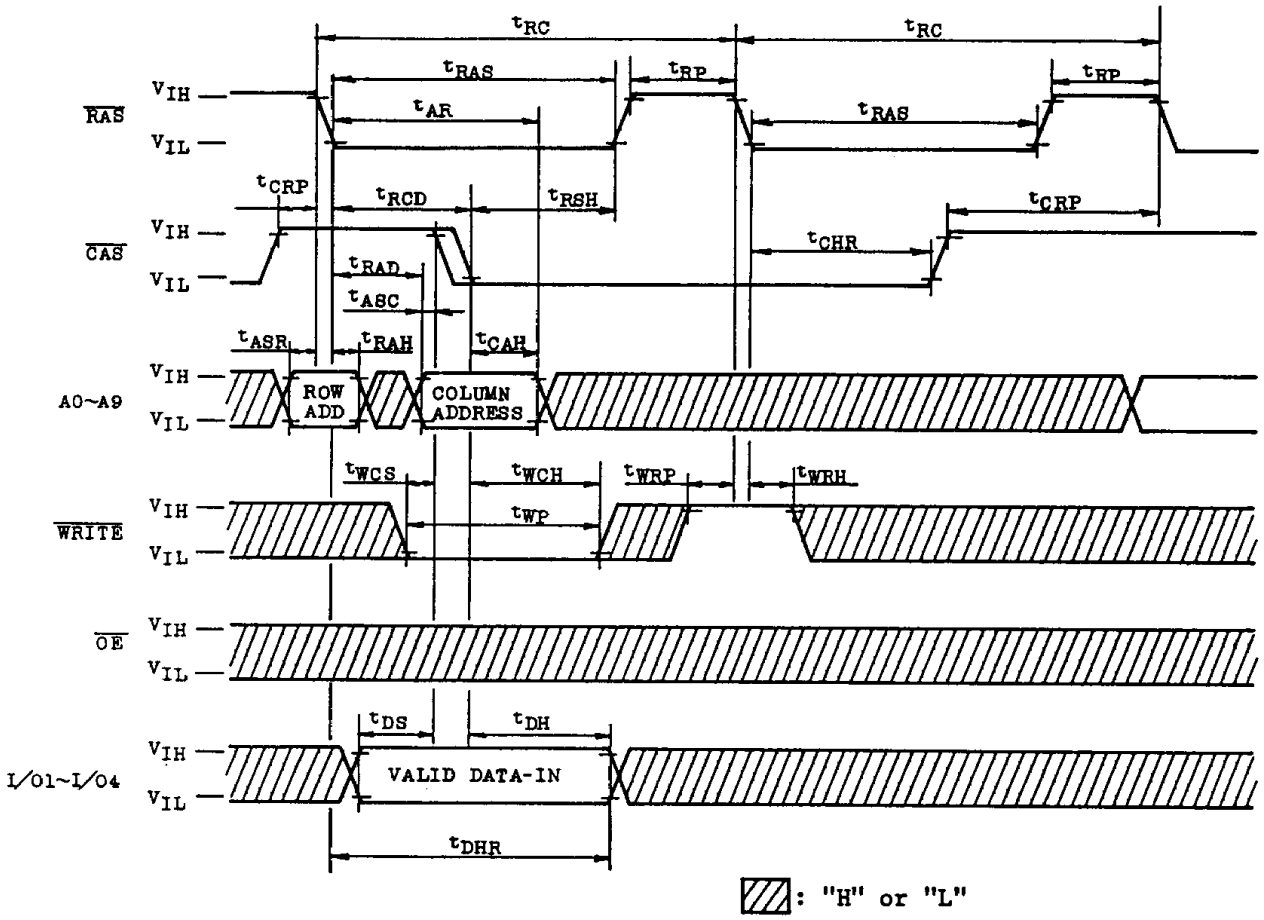


Note: $\overline{OE}$, A0 ∿ A9="H" or "L" ▨ : "H" or "L"

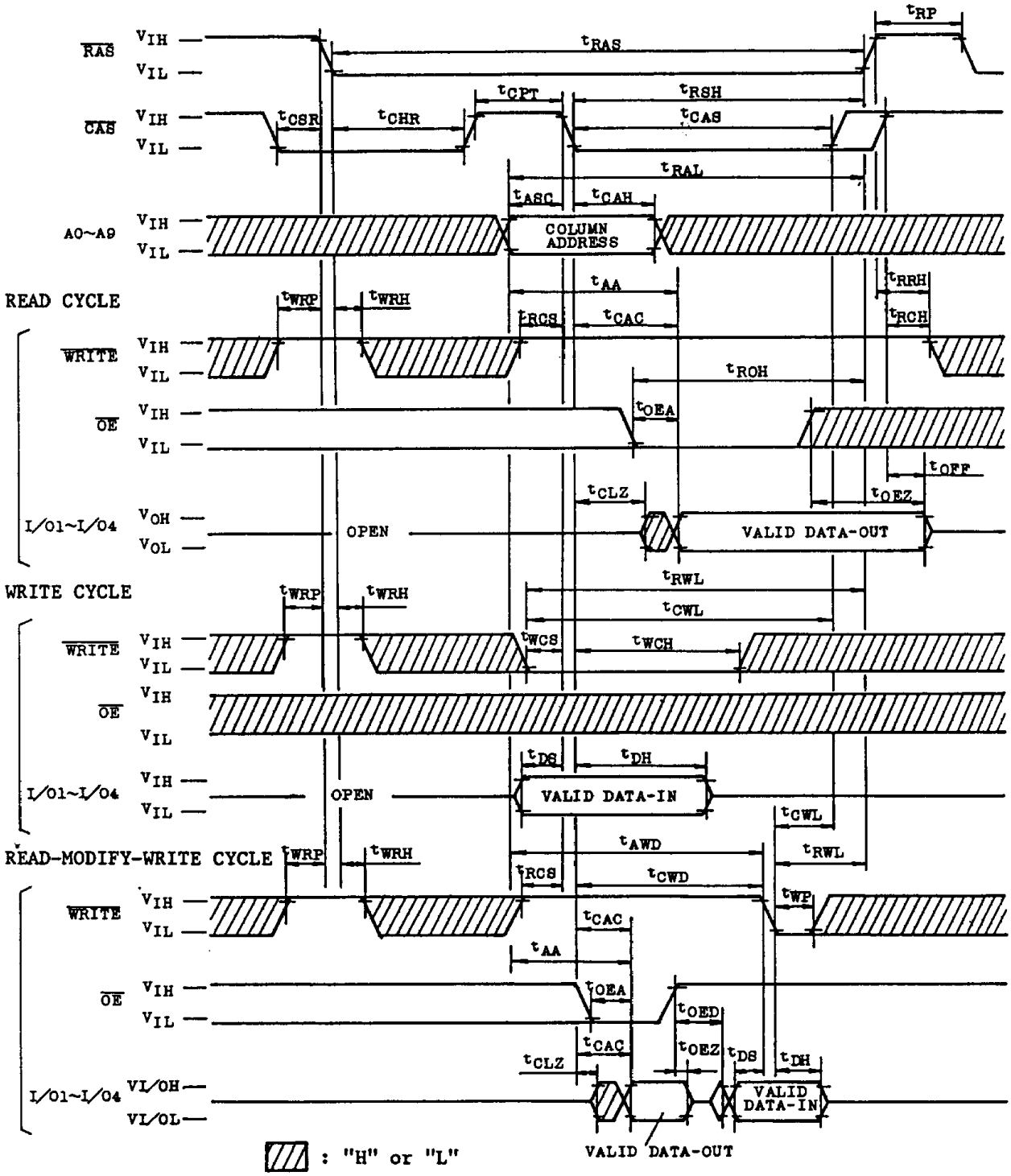
HIDDEN REFRESH CYCLE (READ)



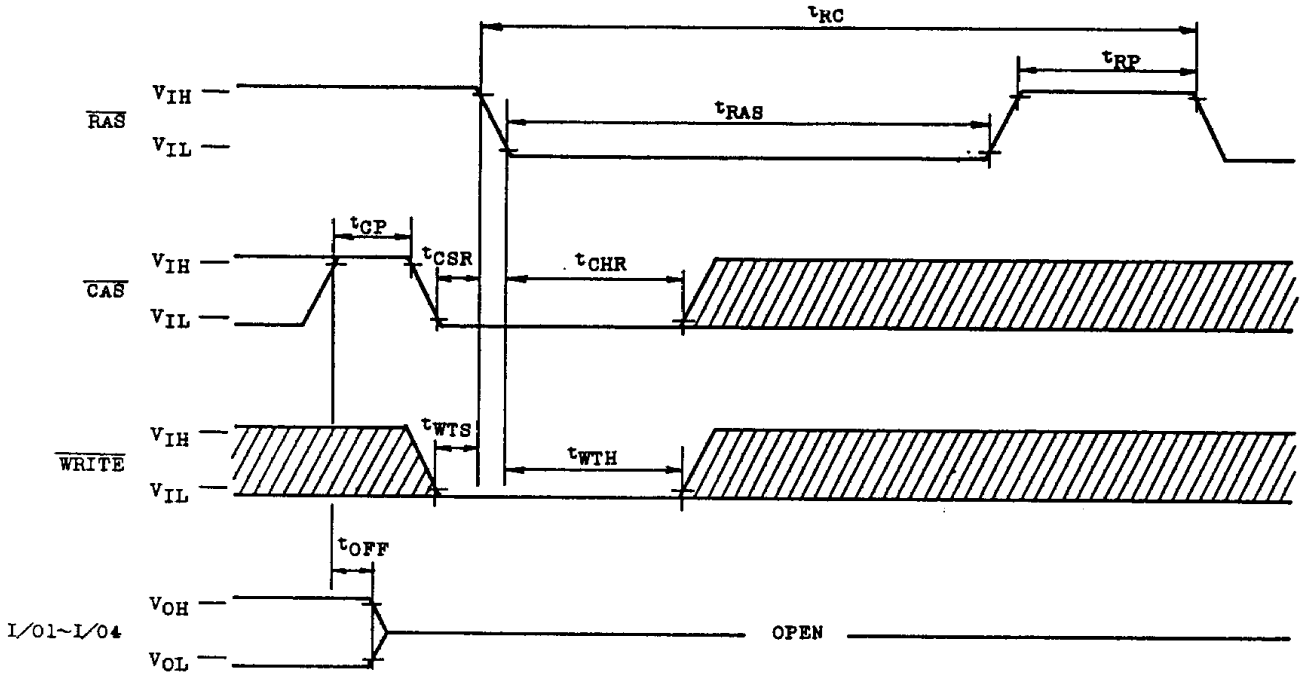
HIDDEN REFRESH CYCLE (WRITE)



$\overline{CAS}$ BEFORE $\overline{RAS}$ REFRESH COUNTER TEST CYCLE



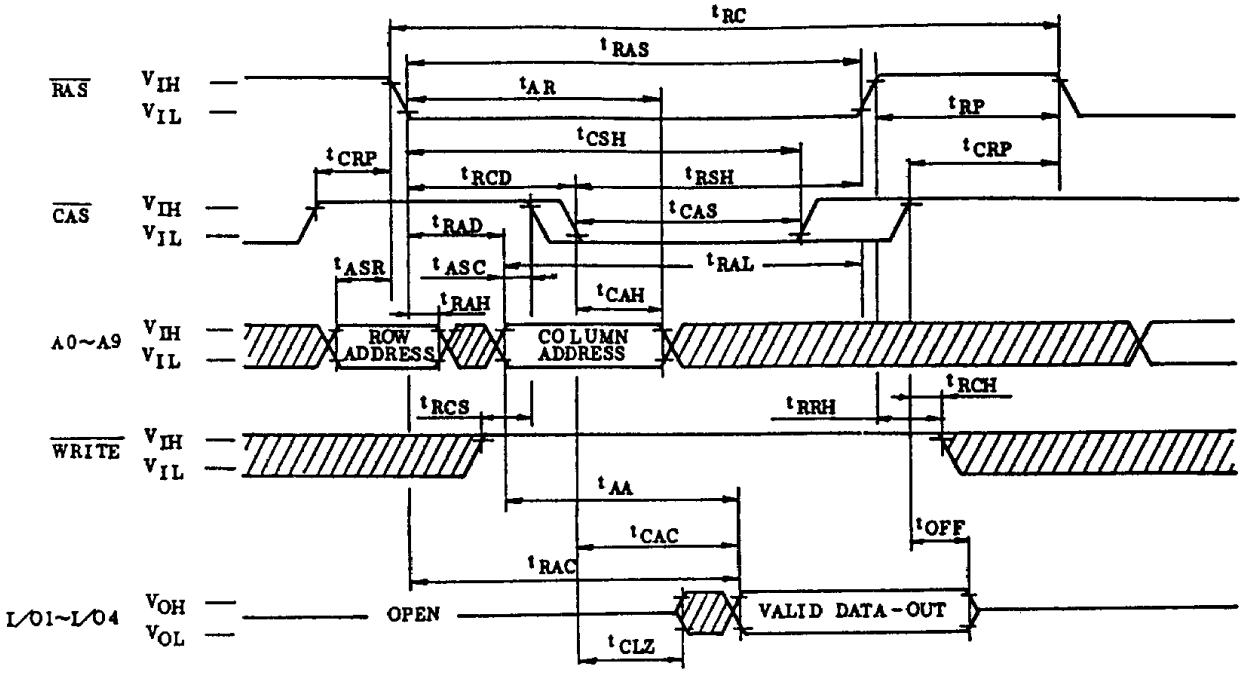
$\overline{\text{WRITE}}$, $\overline{\text{CAS}}$ BEFORE $\overline{\text{RAS}}$ REFRESH CYCLE



$\overline{\text{OE}}$, A0 ∿ A9: "H" or "L"

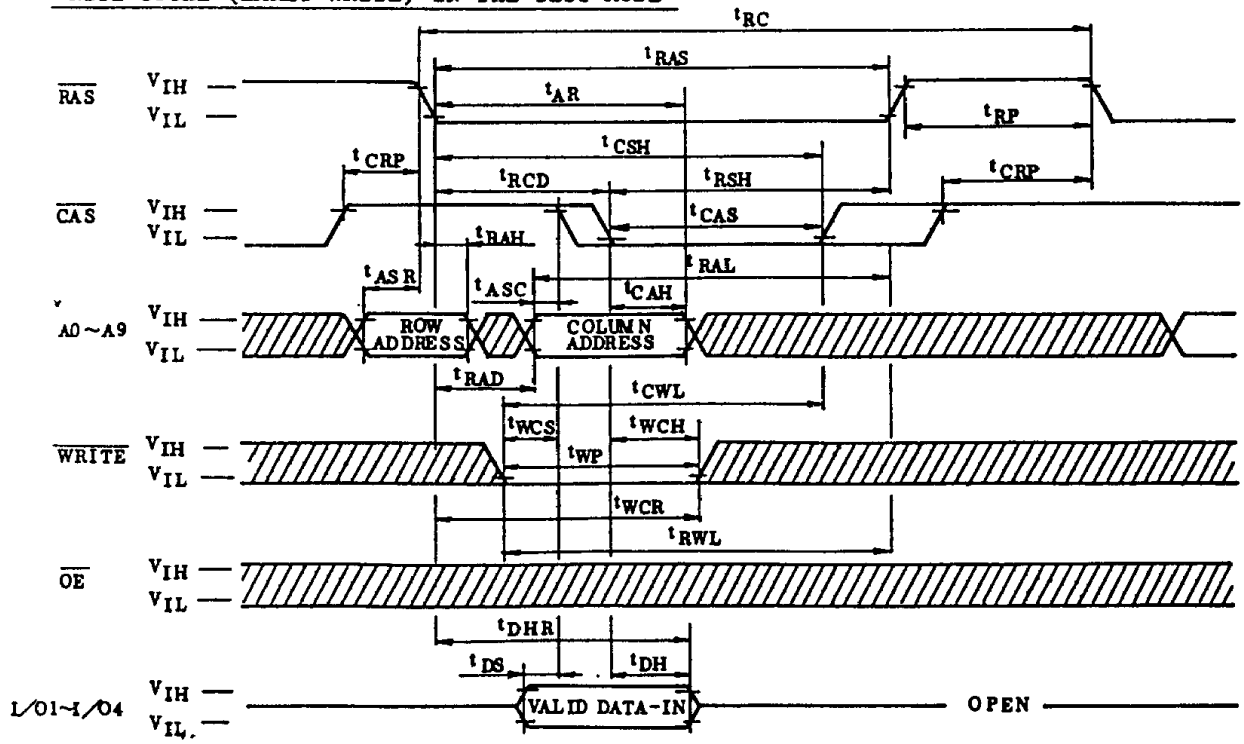
▨: "H" or "L"

READ CYCLE IN THE TEST MODE

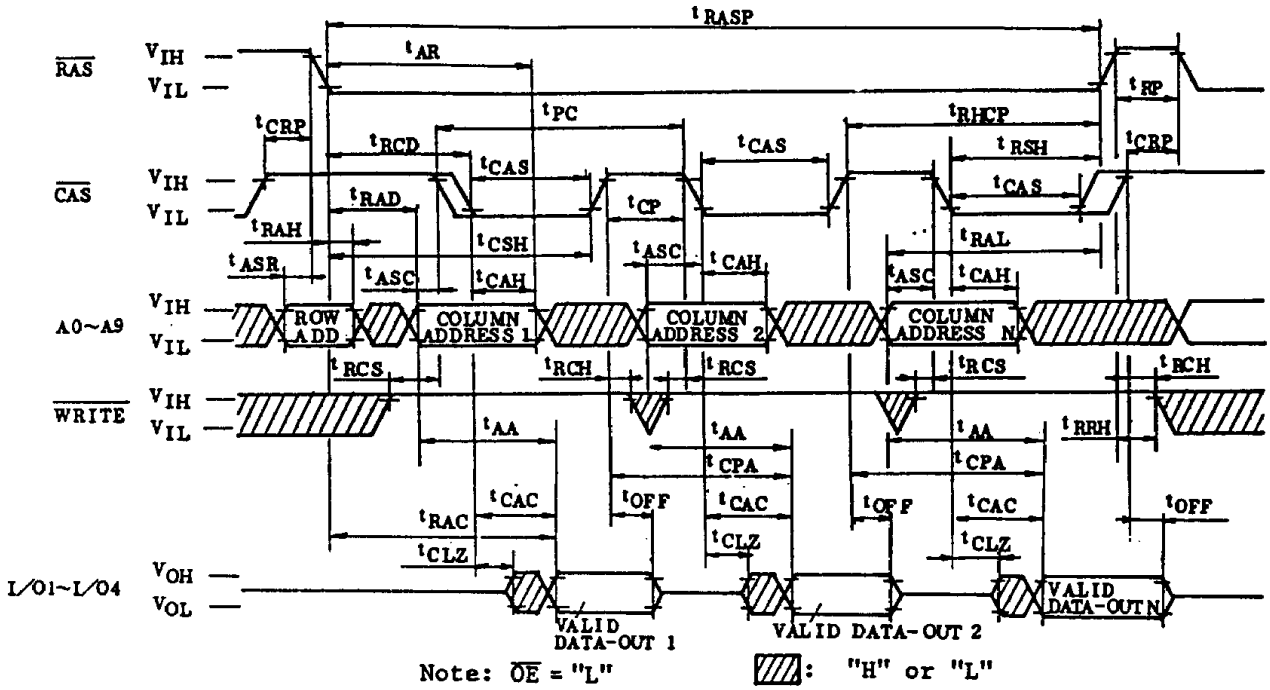


Note: $\overline{OE}$= "L" ▨ : "H" or "L"

WRITE CYCLE (EARLY WRITE) IN THE TEST MODE

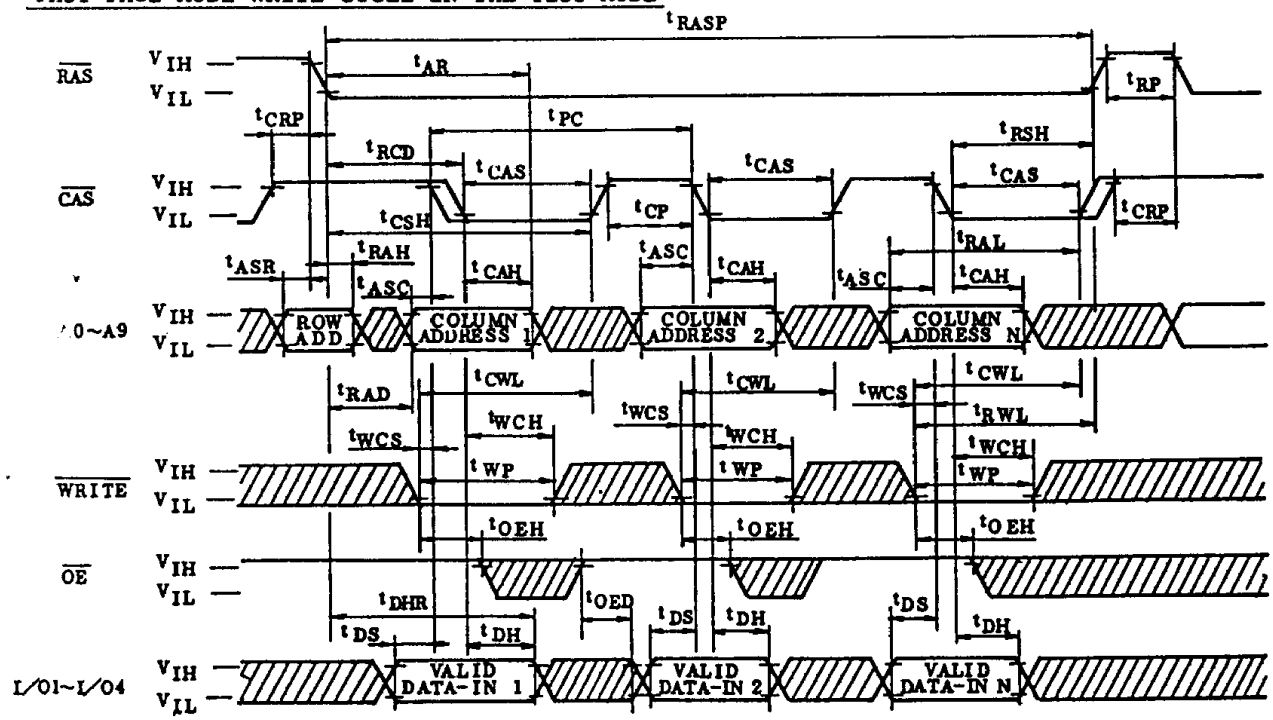


FAST PAGE MODE READ CYCLE IN THE TEST MODE



Note: $\overline{OE}$ = "L" ▨: "H" or "L"

FAST PAGE MODE WRITE CYCLE IN THE TEST MODE



TEST MODE

The TC514400J/Z is the RAM organized 1,048,576 words by 4 bits, it is internally organized 524,288 words by 8 bits. In "Test Mode", data are written into 8 sectors in parallel and retrieved the same way. Aoc is not used. If, upon reading, two bits on one I/O pin are equal (all "1"s or "0"s), the I/O pin indicates a "1". If they were not equal, the I/O pin would indicate a "0". Fig. 1 shows the block diagram of TC514400J/Z. In "Test Mode", the 1M × 4 DRAM can be tested as if it were a 512K × 4 DRAM.

"$\overline{\text{WRITE}}$, $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle puts the device into "Test Mode". And "$\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle" or "$\overline{\text{RAS}}$ Only Refresh Cycle" puts it back into "Normal Mode". In the Test Mode, "$\overline{\text{WRITE}}$, $\overline{\text{CAS}}$ Before $\overline{\text{RAS}}$ Refresh Cycle" Performs the refresh operation with the internal refresh address counter. The "Test Mode" function reduces test times (1/2 in case of N test pattern).

BLOCK DIAGRAM IN THE TEST MODE

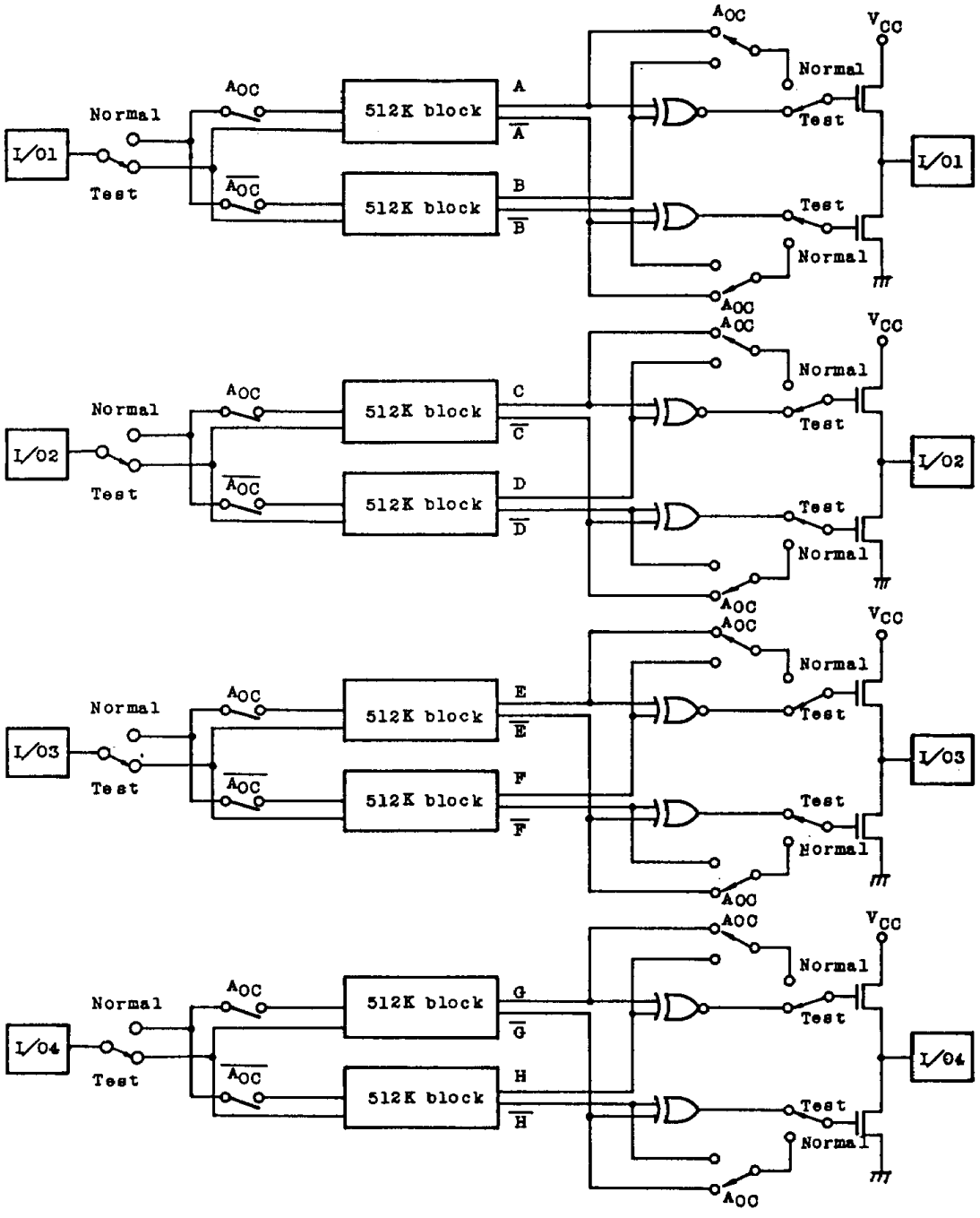


Fig. 1